Quad 2-input NAND gate Rev. 7 — 25 November 2015

1. **General description**

The 74HC00; 74HCT00 is a quad 2-input NAND gate. Inputs include clamp diodes. This enables the use of current limiting resistors to interface inputs to voltages in excess of V_{CC}.

Features and benefits 2.

- Input levels:
 - For 74HC00: CMOS level
 - For 74HCT00: TTL level
- Complies with JEDEC standard no. 7A
- ESD protection:
 - HBM JESD22-A114F exceeds 2000 V
 - MM JESD22-A115-A exceeds 200 V
- Multiple package options
- Specified from -40 °C to +85 °C and from -40 °C to +125 °C

Ordering information 3.

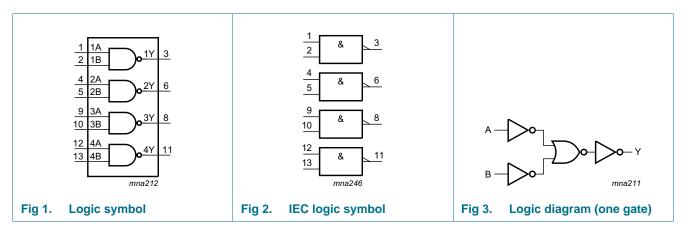
Table 1. **Ordering information**

Type number	Package								
	Temperature range	Name	Description	Version					
74HC00D	–40 °C to +125 °C	SO14	plastic small outline package; 14 leads; body width	SOT108-1					
74HCT00D			3.9 mm						
74HC00DB	–40 °C to +125 °C	SSOP14	plastic shrink small outline package; 14 leads; body	SOT337-1					
74HCT00DB			width 5.3 mm						
74HC00PW	–40 °C to +125 °C	TSSOP14	plastic thin shrink small outline package; 14 leads;	SOT402-1					
74HCT00PW			body width 4.4 mm						
74HC00BQ	–40 °C to +125 °C	DHVQFN14	plastic dual in-line compatible thermal enhanced very	SOT762-1					
74HCT00BQ			thin quad flat package; no leads; 14 terminals; body $2.5 \times 3 \times 0.85$ mm						

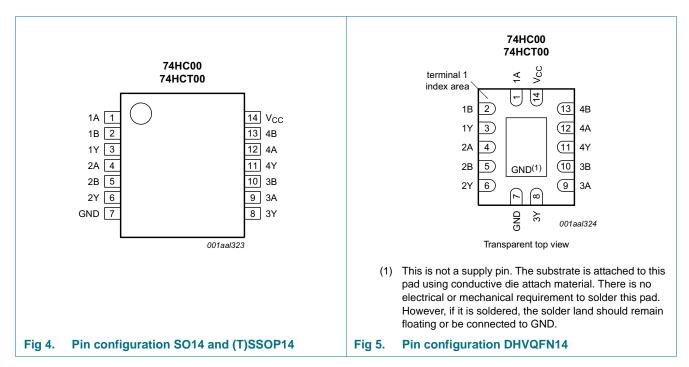


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4. Functional diagram



5. Pinning information



5.1 Pinning

5.2 Pin description

Table 2. Pin description		
Symbol	Pin	Description
1A to 4A	1, 4, 9, 12	data input
1B to 4B	2, 5, 10, 13	data input
1Y to 4Y	3, 6, 8, 11	data output
GND	7	ground (0 V)
V _{CC}	14	supply voltage

6. Functional description

Table 3. Function table^[1]

Input	Output	
nA	nB	nY
L	X	Н
Х	L	Н
Н	Н	L

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care.

7. Limiting values

Table 4.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{CC}	supply voltage			-0.5	+7	V
I _{IK}	input clamping current	$V_{I} < -0.5$ V or $V_{I} > V_{CC}$ + 0.5 V	<u>[1]</u>	-	±20	mA
I _{OK}	output clamping current	V_{O} < -0.5 V or V_{O} > V_{CC} + 0.5 V	<u>[1]</u>	-	±20	mA
lo	output current	$-0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{CC}} + 0.5 \text{ V}$		-	±25	mA
I _{CC}	supply current			-	50	mA
I _{GND}	ground current			-50	-	mA
T _{stg}	storage temperature			-65	+150	°C
P _{tot}	total power dissipation		[2]			
	SO14, (T)SSOP14 and DHVQFN14 packages			-	500	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

For SO14 package: P_{tot} derates linearly with 8 mW/K above 70 °C.
 For (T)SSOP14 packages: P_{tot} derates linearly with 5.5 mW/K above 60 °C.
 For DHVQFN14 packages: P_{tot} derates linearly with 4.5 mW/K above 60 °C.

8. Recommended operating conditions

Table 5. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V)

Symbol	Parameter	Conditions		74HC00			74HCT00		
			Min	Тур	Max	Min	Тур	Max	
V _{CC}	supply voltage		2.0	5.0	6.0	4.5	5.0	5.5	V
VI	input voltage		0	-	V _{CC}	0	-	V _{CC}	V
Vo	output voltage		0	-	V _{CC}	0	-	V _{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	-40	+25	+125	°C
$\Delta t / \Delta V$	input transition rise and fall rate	$V_{CC} = 2.0 V$	-	-	625	-	-	-	ns/V
		$V_{CC} = 4.5 V$	-	1.67	139	-	1.67	139	ns/V
		$V_{CC} = 6.0 V$	-	-	83	-	-	-	ns/V

9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		–40 °C t	o +85 °C	–40 °C to	o +125 °C	Unit
			Min	Тур	Max	Min	Max	Min	Мах	-
74HC00						1	1	1	1	
V _{IH}	HIGH-level	V _{CC} = 2.0 V	-	1.2	-	1.5	-	1.5	-	V
	input voltage	V _{CC} = 4.5 V	-	2.4	-	3.15	-	3.15	-	V
	V _{CC} = 6.0 V	-	3.2	-	4.2	-	4.2	-	V	
V _{IL}	LOW-level input voltage	V _{CC} = 2.0 V	-	0.8	-	-	0.5	-	0.5	V
		V _{CC} = 4.5 V	-	2.1	-	-	1.35	-	1.35	V
	V _{CC} = 6.0 V	-	2.8	-	-	1.8	-	1.8	V	
V _{OH} HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}$									
	output voltage	$I_{O} = -20 \ \mu A; \ V_{CC} = 2.0 \ V$	-	2.0	-	1.9	-	1.9	-	V
		$I_{O} = -20 \ \mu A; \ V_{CC} = 4.5 \ V$	-	4.5	-	4.4	-	4.4	-	V
		$I_{O} = -20 \ \mu A; \ V_{CC} = 6.0 \ V$	-	6.0	-	5.9	-	5.9	-	V
		I_{O} = -4.0 mA; V_{CC} = 4.5 V	-	4.32	-	3.84	-	3.7	-	V
		$I_0 = -5.2 \text{ mA}; V_{CC} = 6.0 \text{ V}$	-	5.81	-	5.34	-	5.2	-	V
V _{OL}	LOW-level	$V_I = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_{O} = 20 \ \mu A; \ V_{CC} = 2.0 \ V$	-	0	-	-	0.1	-	0.1	V
		$I_{O} = 20 \ \mu A; \ V_{CC} = 4.5 \ V$	-	0	-	-	0.1	-	0.1	V
		$I_{O} = 20 \ \mu A; \ V_{CC} = 6.0 \ V$	-	0	-	-	0.1	-	0.1	V
		I_{O} = 4.0 mA; V_{CC} = 4.5 V	-	0.15	-	-	0.33	-	0.4	V
		$I_{O} = 5.2 \text{ mA}; V_{CC} = 6.0 \text{ V}$	-	0.16	-	-	0.33	-	0.4	V
I	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 6.0 \text{ V}$	-	-	-	-	±1	-	±1	μΑ
I _{CC}	supply current		-	-	-	-	20	-	40	μΑ

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Symbol	Parameter	Conditions		25 °C		–40 °C to +85 °C		–40 °C to +125 °C		Unit
			Min	Тур	Max	Min	Max	Min	Max	1
CI	input capacitance		-	3.5	-	-	-	-	-	pF
74HCT0	0					1				
V _{IH}	HIGH-level input voltage	V_{CC} = 4.5 V to 5.5 V	-	1.6	-	2.0	-	2.0	-	V
V _{IL}	LOW-level input voltage	V_{CC} = 4.5 V to 5.5 V	-	1.2	-	-	0.8	-	0.8	V
V _{OH}	V _{OH} HIGH-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
		I _O = -20 μA	-	4.5	-	4.4	-	4.4	-	V
	I _O = -4.0 mA	-	4.32	-	3.84	-	3.7	-	V	
V _{OL}	/ _{OL} LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
	output voltage	$I_{O} = 20 \ \mu A; V_{CC} = 4.5 \ V$	-	0	-	-	0.1	-	0.1	V
		$I_0 = 5.2 \text{ mA}; V_{CC} = 6.0 \text{ V}$	-	0.15	-	-	0.33	-	0.4	V
I	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 6.0 V$	-	-	-	-	±1	-	±1	μA
I _{CC}	supply current		-	-	-	-	20	-	40	μA
ΔI _{CC}	additional supply current	per input pin; $V_I = V_{CC} - 2.1 \text{ V}; I_O = 0 \text{ A};$ other inputs at V_{CC} or GND; $V_{CC} = 4.5 \text{ V}$ to 5.5 V	-	150	-	-	675	-	735	μA
CI	input capacitance		-	3.5	-	-	-	-	-	pF

Table 6. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

10. Dynamic characteristics

Table 7. Dynamic characteristics

 $GND = 0 V; C_L = 50 pF;$ for test circuit see Figure 7.

Symbol	Parameter	Conditions			25 °C		-40 °C to	o +125 ℃	Unit
				Min	Тур	Max	Max (85 °C)	Max (125 °C)	_
74HC00									
t _{pd}	propagation delay	nA, nB to nY; see Figure 6	<u>[1]</u>						
	V _{CC} = 2.0 V		-	25	-	115	135	ns	
		V _{CC} = 4.5 V		-	9	-	23	27	ns
		V _{CC} = 5.0 V; C _L = 15 pF		-	7	-	-	-	ns
		V _{CC} = 6.0 V		-	7	-	20	23	ns
t _t	transition time	see Figure 6	<u>[2]</u>						
		V _{CC} = 2.0 V		-	19	-	95	110	ns
		V _{CC} = 4.5 V		-	7	-	19	22	ns
		V _{CC} = 6.0 V		-	6	-	16	19	ns

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Symbol	Parameter	Conditions		25 °C			–40 °C to	Unit	
				Min	Тур	Max	Max (85 °C)	Max (125 °C)	-
C _{PD}	power dissipation capacitance	per package; $V_I = GND$ to V_{CC}	<u>[3]</u>	-	22	-	-	-	pF
74HCT00)					1	1	1	
t _{pd}	propagation delay	nA, nB to nY; see Figure 6	<u>[1]</u>						
		V _{CC} = 4.5 V		-	12	-	24	29	ns
		V _{CC} = 5.0 V; C _L = 15 pF		-	10	-	-	-	ns
t _t	transition time	$V_{CC} = 4.5 V$; see <u>Figure 6</u>	[2]	-	-	-	29	22	ns
C _{PD}	power dissipation capacitance	per package; V _I = GND to V _{CC} – 1.5 V	<u>[3]</u>	-	22	-	-	-	pF

Table 7. Dynamic characteristics ... continued GND = 0 V: $C_1 = 50$ pF: for test circuit see Figure 7.

[1] t_{pd} is the same as t_{PHL} and t_{PLH} .

[2] t_t is the same as t_{THL} and t_{TLH} .

[3] C_{PD} is used to determine the dynamic power dissipation (P_D in μ W):

 $\mathsf{P}_{\mathsf{D}} = \mathsf{C}_{\mathsf{P}\mathsf{D}} \times \mathsf{V}_{\mathsf{C}\mathsf{C}}{}^2 \times \mathsf{f}_i \times \mathsf{N} + \boldsymbol{\Sigma} \; (\mathsf{C}_{\mathsf{L}} \times \mathsf{V}_{\mathsf{C}\mathsf{C}}{}^2 \times \mathsf{f}_o) \; \text{where:} \;$

 f_i = input frequency in MHz;

 f_o = output frequency in MHz;

 C_L = output load capacitance in pF;

 V_{CC} = supply voltage in V;

N = number of inputs switching;

 $\sum (C_L \times V_{CC}^2 \times f_o)$ = sum of outputs.

11. Waveforms

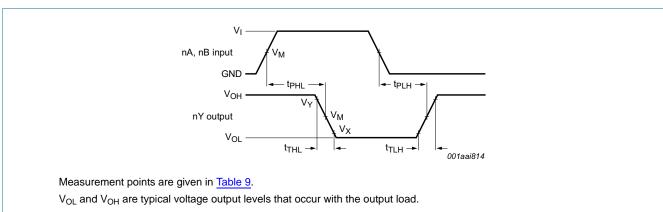


Fig 6. Input to output propagation delays

Table 8. Measurement points

Туре	Input	Output				
	V _M	V _M	V _X	V _Y		
74HC00	0.5V _{CC}	0.5V _{CC}	0.1V _{CC}	0.9V _{CC}		
74HCT00	1.3 V	1.3 V	0.1V _{CC}	0.9V _{CC}		

74HC_HCT00
Product data sheet

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NXP Semiconductors

74HC00; 74HCT00

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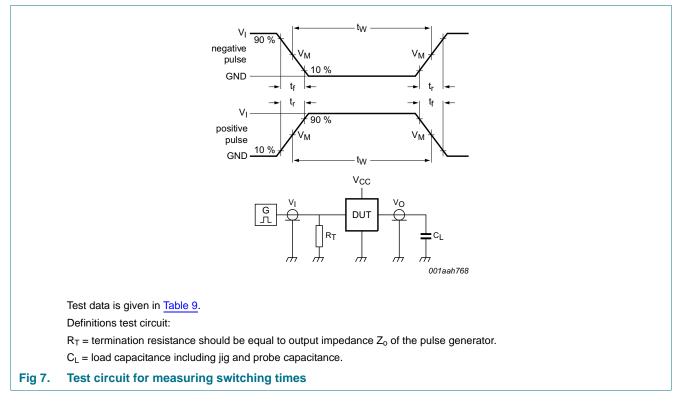


Table 9. Test data

Туре	Input L		Load	Test
	VI	t _r , t _f	CL	
74HC00	V _{CC}	6.0 ns	15 pF, 50 pF	t _{PLH} , t _{PHL}
74HCT00	3.0 V	6.0 ns	15 pF, 50 pF	t _{PLH} , t _{PHL}

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12. Package outline

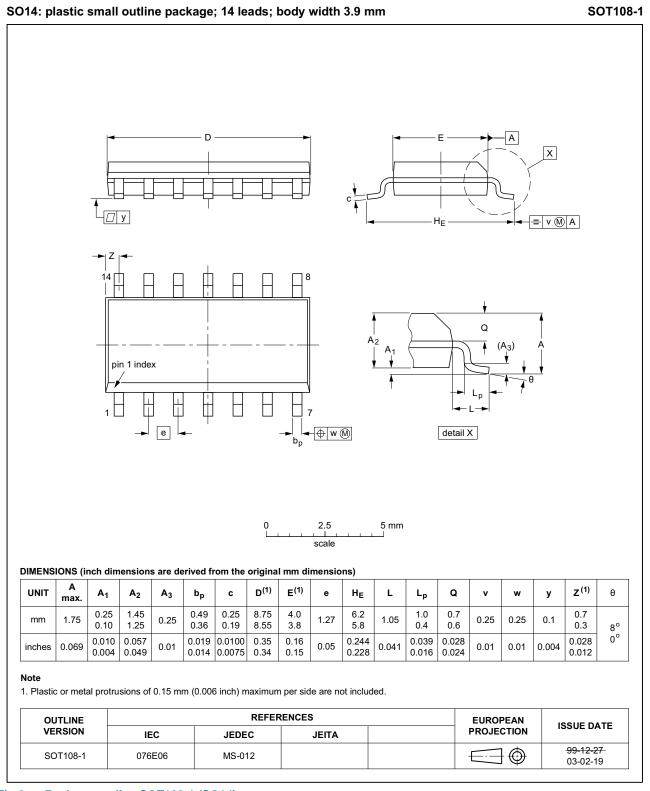
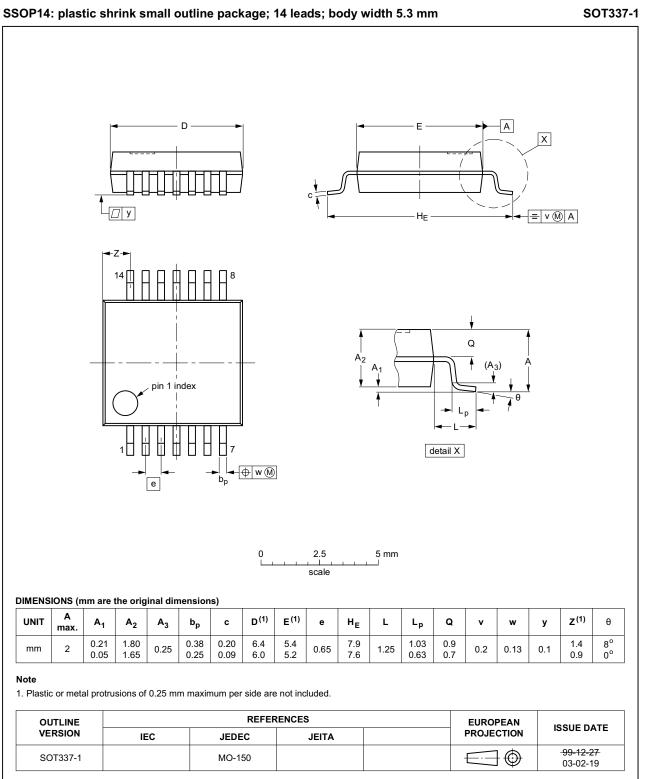


Fig 8. Package outline SOT108-1 (SO14)

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Package outline SOT337-1 (SSOP14) Fig 9.

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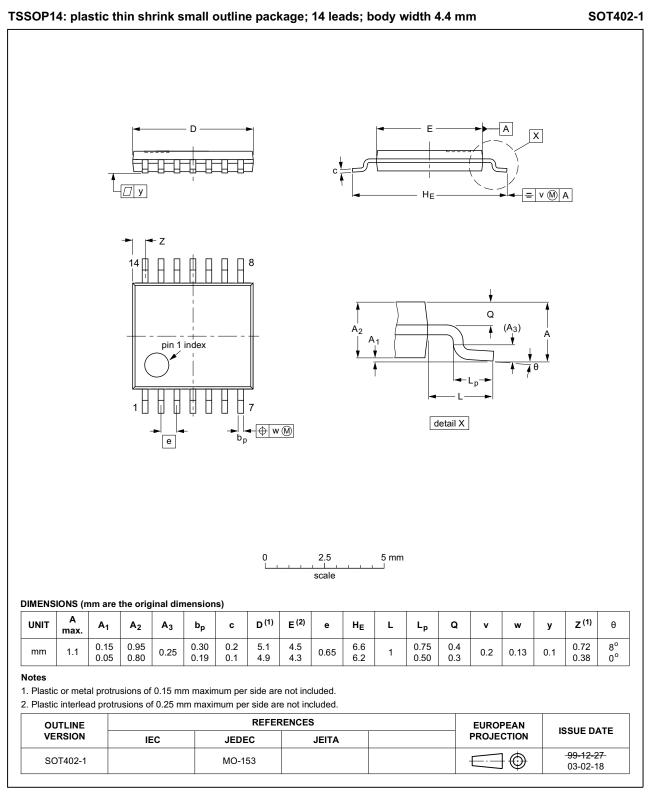
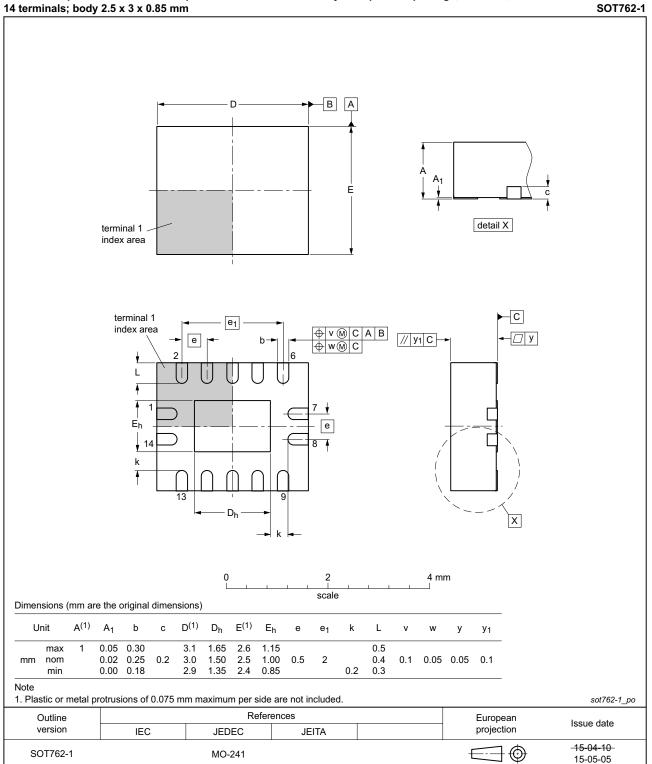


Fig 10. Package outline SOT402-1 (TSSOP14)

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DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads;

Fig 11. Package outline SOT762-1 (DHVQFN14)

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13. Abbreviations

Table 10. Abbreviations					
Acronym	Description				
CMOS	Complementary Metal-Oxide Semiconductor				
DUT	Device Under Test				
ESD	ElectroStatic Discharge				
HBM	Human Body Model				
LSTTL	Low-power Schottky Transistor-Transistor Logic				
MM	Machine Model				
TTL	Transistor-Transistor Logic				

14. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74HC_HCT00 v.7	20151125	Product data sheet	-	74HC_HCT00 v.6
Modifications:	Type numbers 74HC00N and 74HCT00N (SOT27-1) removed.			
74HC_HCT00 v.6	20111214	Product data sheet	-	74HC_HCT00 v.5
Modifications:	 Legal pages update 	d.		
74HC_HCT00 v.5	20101125	Product data sheet	-	74HC_HCT00 v.4
74HC_HCT00 v.4	20100111	Product data sheet	-	74HC_HCT00 v.3
74HC_HCT00 v.3	20030630	Product data sheet	-	74HC_HCT00_CNV v.2
74HC_HCT00_CNV v.2	19970826	Product specification	-	-

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74HC HCT00

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